



## AN 370

SIMS Detection Limits of Selected Elements  
in GaN Under Normal Depth Profiling Conditions

May 7, 2007 (Version 4.0)

O <sub>2</sub> /SIMS Positive Secondary Ion Detection		Cs/SIMS Negative Secondary Ion Detection		Cs/SIMS Positive Secondary Ion Detection (CsM <sup>+</sup> )	
Element	DL (atoms/cm <sup>3</sup> )	Element	DL (atoms/cm <sup>3</sup> )	Element	DL (atoms/cm <sup>3</sup> )
Be	1E+14	H*	8E+16 - 2E+17	Mg	5E+15
Li	1E+14	C*	5E+15 - 2E+16	Zn	1E+16
B	1E+15	O*	1E+16 - 3E+16		
Na	5E+14	Si	3E+15		
Mg	5E+14	As	5E+15		
Al	1E+15				

\*Varies with vacuum conditions

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